

Title (en)

METHOD TO USE A PROBE TO MONITOR INTERFACIAL CHANGES OF CAPACITANCE AND RESISTANCE

Title (de)

VERFAHREN ZUR VERWENDUNG EINER SONDE ZUR ÜBERWACHUNG DER GRENZFLÄCHENVERÄNDERUNGEN VON KAPAZITÄT UND WIDERSTAND

Title (fr)

PROCÉDÉ D'UTILISATION D'UNE SONDE POUR SURVEILLER DES MODIFICATIONS INTERFACIALES DE CAPACITÉ ET DE RÉSISTANCE

Publication

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Application

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Abstract (en)

[origin: WO2013009251A1] The present invention relates to method to use a probe (1) adapted to monitor interfacial changes of capacitance and resistance. It is specifically taught that the probe consist of one single electrode, which electrode is in the form of a planar coil (11).

IPC 8 full level

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CPC (source: EP)

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Citation (search report)

- [X] US 6782736 B1 20040831 - HAMMER ERLING [NO]
- [X] US 2008174306 A1 20080724 - BRADY STEVEN K [US]
- [X] EP 1747461 B1 20101215 - RANDOX LAB LTD [GB]
- [A] EP 1602921 A1 20051207 - SAMSUNG ELECTRONICS CO LTD [KR]
- See references of WO 2013009251A1

Designated contracting state (EPC)

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